

AMENDMENTS TO THE CLAIMS

(IN FORMAT COMPLIANT WITH THE REVISION TO 37 CFR 1.121)

Please cancel claims 18, 19, 23 and 26 without prejudice.

1. (CURRENTLY AMENDED) An apparatus comprising:

a first device comprising (i) a first gate configured to receive an input voltage ranging from up to twice a first supply voltage with respect to a second supply voltage to at least said  
5 second supply voltage, (ii) a first drain configured to receive said first supply voltage, and (iii) a first source coupled to a first output; ~~and~~

a first resistive element having (i) a first side coupled to said first source and (ii) a second side configured to receive  
10 said second supply voltage, wherein said apparatus is arranged such that a maximum voltage drop across a gate oxide of said first device does not exceed a difference between said first supply voltage and said second supply voltage and a voltage drop from said first gate to said first output is non-linear as a function of said  
15 input voltage; and

a multiplexer configured to multiplex said first output and a second output to a third output.

2. (CANCELED)

3. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said first device is configured in a source-follow configuration.

4. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said first device comprises an NMOS device.

5. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said first device comprises a native NMOS device.

6. (CANCELED)

7. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said first device comprises a PMOS device.

8. (PREVIOUSLY PRESENTED) The apparatus according to claim 1, wherein said first device comprises a native PMOS device.

9. (ORIGINAL) The apparatus according to claim 1, wherein said first supply voltage comprises a ground voltage.

10. (ORIGINAL) The apparatus according to claim 1, wherein said second supply voltage comprises a ground voltage.

11. (PREVIOUSLY PRESENTED) A method for implementing voltage protection comprising the steps of:

configuring a first device to have (i) a first gate for receiving an input voltage ranging from up to twice a first supply voltage with respect to a second supply voltage to at least said second supply voltage, (ii) a first drain for receiving said first supply voltage, and (iii) a first source coupled to a first output; and

configuring a first resistive element to have (i) a first side coupled to said first source and (ii) a second side for receiving said second supply voltage, wherein said first device and said first resistive element are arranged such that a maximum voltage drop across a gate oxide of said first device does not exceed a difference between said first supply voltage and said second supply voltage and a voltage drop from said first gate to said first output is non-linear as a function of said input voltage; and

multiplexing said first output and a second output to a third output.

12. (CANCELED)

13. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein said first device is configured in a source-follow configuration.

14. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein said first device comprises an NMOS device.

15. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein said first device comprises a PMOS device.

16. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein said first device comprises a native NMOS device.

17. (PREVIOUSLY PRESENTED) The method according to claim 11, wherein said first device comprises a native PMOS device.

18. (CANCELED)

19. (CANCELED)

20. (PREVIOUSLY PRESENTED) An apparatus comprising:  
a first stage comprising (A) a first device comprising  
(i) a first gate configured to receive an input voltage ranging from greater than a first supply voltage to at least a second

5 supply voltage, (ii) a first drain configured to receive said first supply voltage, and (iii) a first source directly connected to an output, and (B) a first resistive element having (i) a first side coupled to said first source and (ii) a second side configured to receive said second supply voltage; and .

10 a second stage comprising (A) a second device comprising (i) a second gate configured to receive said input voltage, (ii) a second drain configured to receive said second supply voltage, and (iii) a second source directly connected to said output, and (B) a second resistive element having a first side coupled to said second  
15 source and a second side configured to receive said first supply voltage, wherein said apparatus is arranged such that a maximum voltage drop across each gate oxide of said first device and said second device does not exceed a difference between said first supply voltage and said second supply voltage.

21. (CURRENTLY AMENDED) The apparatus according to claim  
~~19~~ 1, further comprising a second device having (i) a second gate configured to receive said input voltage, (ii) a second drain configured to receive said second supply voltage, and (iii) a  
5 second source coupled to said second output.

22. (PREVIOUSLY PRESENTED) The apparatus according to claim 21, further comprising a second resistive element having (i)

a first side coupled to said second source and (ii) a second side configured to receive said first supply voltage.

23. (CANCELED)

24. (CURRENTLY AMENDED) The method according to claim 23 11, further comprising the step of:

configuring a second device to have (i) a second gate for receiving said input voltage, (ii) a second drain for receiving said second supply voltage, and (iii) a second source coupled to said second output.

25. (PREVIOUSLY PRESENTED) The method according to claim 24, further comprising the step of:

configuring a second resistive element to have (i) a first side coupled to said second source and (ii) a second side for receiving said first supply voltage.

26. (CANCELED)